The 28th IEEE Asian Test Symposium (ATS'19)

Kolkata, West Bengal, India

10th -13th December 2019

http://ats2019.iiests.ac.in/

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Call for papers

The Asian Test Symposium (ATS) provides an open forum for researchers and industrial practitioners from all countries of the world to exchange innovative ideas on system, board, and device testing with design, manufacturing and field consideration in mind. The theme for the symposium this year is "Testing in the Era of AI and Autonomous System".

Scope

Original papers on, but not limited to, the following areas are invited.

- Analog/Mixed-Signal Test
- Automatic Test Generation
- Board Test and Diagnosis
- Boundary Scan Test
- Built-In Self-Test (BIST)
- Defect-Based Test
- Delay and Performance Test
- Dependability and Functional Safety
- Design for Test (DFT)
- Diagnosis and Silicon Debug
- Economic of Test
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- GPU Test
- High-Speed I/O Test
- Low-Power IC Test
- Memory Test and Repair
- Test for MEMS and Microfluidic Systems
- Multi-/Many-core Processor Test
- Test for Nanoscale Devices and Emerging Technologies
- On-line Test
- Power/Thermal/Reliability Issues in Test
- Reconfigurable System Test
- Test for Biomedical Circuits and Systems
- RF Test
- Hardware-oriented Security and Trust
- Self-Repair
- Test for Sensors and IoT
- SiP, Stacked, 3D IC Test
- Standards in Test
- Machine Learning in Test
- Test Compression
- Test Quality
- Test Synthesis
- Validation and Verification
- Yield Analysis and Enhancement
- Test for Reversible and Quantum Circuits

Submissions (Submission website: https://easychair.org/conferences/?conf=ats2019)

Regular Sessions: The ATS'19 Program Committee invites original, unpublished paper submissions on the above topics. Paper submissions should be complete manuscripts, not exceeding six pages (including figures, tables, and bibliography) in a standard IEEE two-column format. The submission will be considered evidence that upon acceptance the author(s) will submit a final camera-ready version of the paper or inclusion in the proceedings, and will present the paper at the symposium. ATS reserves the right to remove from IEEE Xplore papers not presented at the symposium. The best paper will be selected by the ATS'19 Program Committee for the best paper award based on the criteria of innovation, potential impact, and presentation quality.

Key Dates:

- Submission deadline: **14th June 2019**
- Notification of acceptance: **16th August 2019**
- Camera-ready manuscript: **13th September 2019**